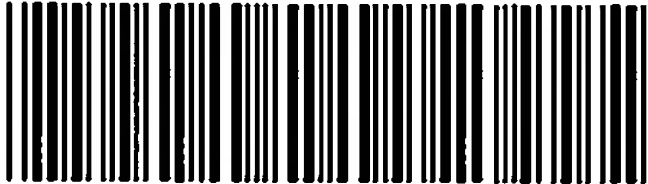


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/606,138	AYYAVU ET AL.	
	Examiner	Art Unit	
	James K. Trujillo	2116	

SEARCHED			
Class	Subclass	Date	Examiner
713	300,320, 322,323, 324	12/8/2004	JKT
updated		5/9/2005	JKT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Databases: EAST NPL: IEEE, ACM	12/8/2004	JKT
updated	5/9/2005	JKT